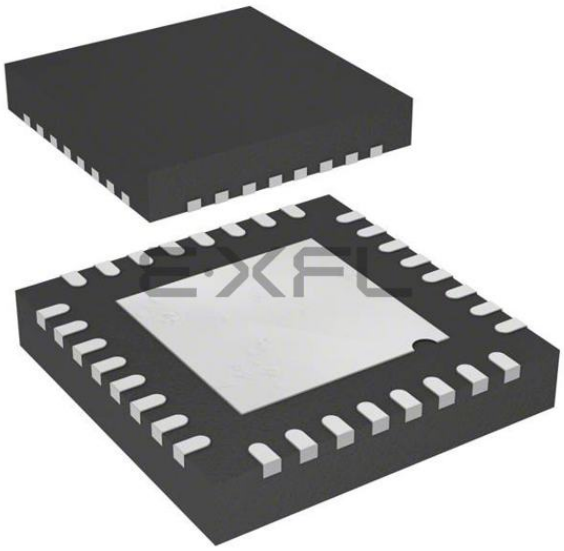

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	512 x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-VFQFN Exposed Pad
Supplier Device Package	32-VFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af6246ucy

5 Product overview

This section describes the family features that are implemented in the products covered by this datasheet.

For more detailed information on each feature please refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual (RM0016).

5.1 STM8A central processing unit (CPU)

The 8-bit STM8A core is a modern CISC core and has been designed for code efficiency and performance. It contains 21 internal registers (six directly addressable in each execution context), 20 addressing modes including indexed indirect and relative addressing and 80 instructions.

5.1.1 Architecture and registers

- Harvard architecture
- 3-stage pipeline
- 32-bit wide program memory bus with single cycle fetching for most instructions
- X and Y 16-bit index registers, enabling indexed addressing modes with or without offset and read-modify-write type data manipulations
- 8-bit accumulator
- 24-bit program counter with 16-Mbyte linear memory space
- 16-bit stack pointer with access to a 64 Kbyte stack
- 8-bit condition code register with seven condition flags for the result of the last instruction.

5.1.2 Addressing

- 20 addressing modes
- Indexed indirect addressing mode for look-up tables located anywhere in the address space
- Stack pointer relative addressing mode for efficient implementation of local variables and parameter passing

5.1.3 Instruction set

- 80 instructions with 2-byte average instruction size
- Standard data movement and logic/arithmetic functions
- 8-bit by 8-bit multiplication
- 16-bit by 8-bit and 16-bit by 16-bit division
- Bit manipulation
- Data transfer between stack and accumulator (push/pop) with direct stack access
- Data transfer using the X and Y registers or direct memory-to-memory transfers

5.4.2 Write protection (WP)

Write protection in application mode is intended to avoid unintentional overwriting of the memory. The write protection can be removed temporarily by executing a specific sequence in the user software.

5.4.3 Protection of user boot code (UBC)

If the user chooses to update the Flash program memory using a specific boot code to perform in application programming (IAP), this boot code needs to be protected against unwanted modification.

In the STM8A a memory area of up to 32 Kbyte can be protected from overwriting at user option level. Other than the standard write protection, the UBC protection can exclusively be modified via the debug interface, the user software cannot modify the UBC protection status.

The UBC memory area contains the reset and interrupt vectors and its size can be adjusted in increments of 512 bytes by programming the UBC and NUBC option bytes (see *Section 9: Option bytes on page 44*).

Figure 2. Flash memory organization of STM8AF6246/48/66/68

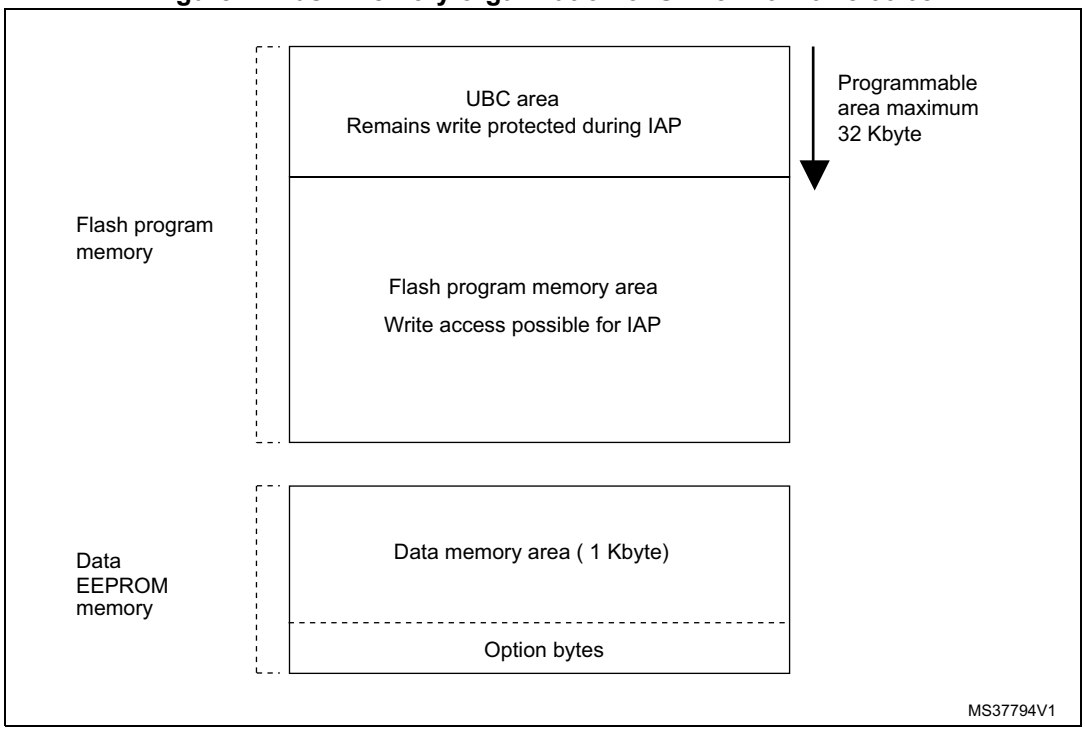


Table 8. STM8AF6246/48/66/68 (32 Kbyte) microcontroller pin description(1)(2) (continued)

Pin number		Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
LQFP48	VFQFPN/LQFP32			floating	wpu	Ext. interrupt	High sink	Speed	OD	PP			
24		PE6/AIN9	I/O	**X**	X	X	-	O1	X	X	**Port E7**	Analog input 9	-
25	17	PE5/SPI_NSS	I/O	**X**	X	X	-	O1	X	X	**Port E5**	SPI master/slave select	-
26	18	PC1/TIM1_CH1	I/O	**X**	X	X	HS	O3	X	X	**Port C1**	Timer 1 - channel 1	-
27	19	PC2/TIM1_CH2	I/O	**X**	X	X	HS	O3	X	X	**Port C2**	Timer 1- channel 2	-
28	20	PC3/TIM1_CH3	I/O	**X**	X	X	HS	O3	X	X	**Port C3**	Timer 1 - channel 3	-
29	21	PC4/TIM1_CH4	I/O	**X**	X	X	HS	O3	X	X	**Port C4**	Timer 1 - channel 4	-
30	22	PC5/SPI_SCK	I/O	**X**	X	X		O3	X	X	**Port C5**	SPI clock	-
31	-	V_{SSIO_2}	S	-	-	-	-	-	-	-	I/O ground		-
32	-	V_{DDIO_2}	S	-	-	-	-	-	-	-	I/O power supply		-
33	23	PC6/SPI_MOSI	I/O	**X**	X	X	-	O3	X	X	**Port C6**	SPI master out/ slave in	-
34	24	PC7/SPI_MISO	I/O	**X**	X	X	-	O3	X	X	**Port C7**	SPI master in/ slave out	-
35	-	PG0	I/O	**X**	X	-	-	O1	X	X	**Port G0**	-	-
36	-	PG1	I/O	**X**	X	-	-	O1	X	X	**Port G1**	-	-
37	-	PE3/TIM1_BKIN	I/O	**X**	X	X	-	O1	X	X	**Port E3**	Timer 1 - break input	-
38	-	PE2/I^2C_SDA	I/O	**X**	-	X	-	O1	T(6)	-	**Port E2**	I^2C data	-
39	-	PE1/I^2C_SCL	I/O	**X**	-	X	-	O1	T(6)	-	**Port E1**	I^2C clock	-
40	-	PE0/CLK_CCO	I/O	**X**	X	X	-	O3	X	X	**Port E0**	Configurable clock output	-
41	25	PD0/TIM3_CH2	I/O	**X**	X	X	HS	O3	X	X	**Port D0**	Timer 3 - channel 2	TIM1_BKIN [AFR3]/ CLK_CCO [AFR2]
42	26	PD1/SWIM(7)	I/O	X	**X**	X	HS	O4	X	X	**Port D1**	SWIM data interface	-
43	27	PD2/TIM3_CH1	I/O	**X**	X	X	HS	O3	X	X	**Port D2**	Timer 3 - channel 1	TIM2_CH3 [AFR1]
44	28	PD3/TIM2_CH2	I/O	**X**	X	X	HS	O3	X	X	**Port D3**	Timer 2 - channel 2	ADC_ETR [AFR0]
45	29	PD4/TIM2_CH1/ BEEP	I/O	**X**	X	X	HS	O3	X	X	**Port D4**	Timer 2 - channel 1	BEEP output [AFR7]
46	30	PD5/ LINUART_TX	I/O	**X**	X	X	-	O1	X	X	**Port D5**	LINUART data transmit	-

Table 10. I/O port hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5014	Port E	PE_ODR	Port E data output latch register	0x00
0x00 5015		PE_IDR	Port E input pin value register	0xXX(1)
0x00 5016		PE_DDR	Port E data direction register	0x00
0x00 5017		PE_CR1	Port E control register 1	0x00
0x00 5018		PE_CR2	Port E control register 2	0x00
0x00 5019	Port F	PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xXX(1)
0x00 501B		PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D		PF_CR2	Port F control register 2	0x00
0x00 501E	Port G	PG_ODR	Port G data output latch register	0x00
0x00 501F		PG_IDR	Port G input pin value register	0xXX(1)
0x00 5020		PG_DDR	Port G data direction register	0x00
0x00 5021		PG_CR1	Port G control register 1	0x00
0x00 5022		PG_CR2	Port G control register 2	0x00

1. Depends on the external circuitry.

Table 11. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 505A	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 505B		FLASH_CR2	Flash control register 2	0x00
0x00 505C		FLASH_NCR2	Flash complementary control register 2	0xFF
0x00 505D		FLASH_FPR	Flash protection register	0x00
0x00 505E		FLASH_NFPR	Flash complementary protection register	0xFF
0x00 505F		FLASH_IAPSR	Flash in-application programming status register	0x40
0x00 5060 to 0x00 5061	Reserved area (2 bytes)			
0x00 5062	Flash	FLASH_PUKR	Flash Program memory unprotection register	0x00
0x00 5063	Reserved area (1 byte)			
0x00 5064	Flash	FLASH_DUKR	Data EEPROM unprotection register	0x00
0x00 5065 to 0x00 509F	Reserved area (59 bytes)			

Table 15. Option bytes (continued)

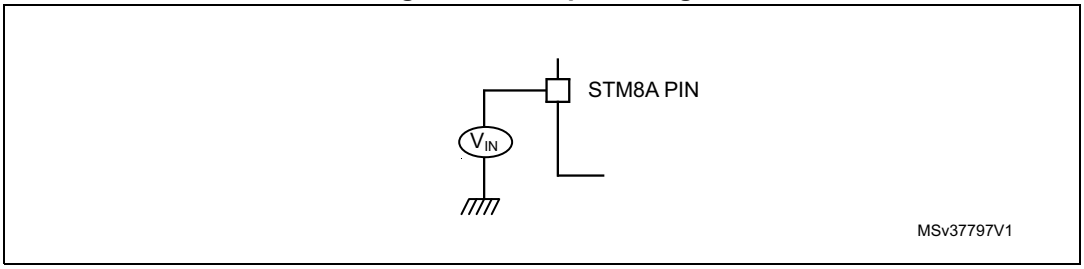
Addr.	Option name	Option byte no.	Option bits								Factory default setting
			7	6	5	4	3	2	1	0	
0x00 480B	TMU	OPT6	TMU[3:0]								0x00
0x00 480C		NOPT6	NTMU[3:0]								0xFF
0x00 480D	Flash wait states	OPT7	Reserved							WAIT STATE	0x00
0x00 480E		NOPT7	Reserved							NWAIT STATE	0xFF
0x00 480F	Reserved										
0x00 4810	TMU	OPT8	TMU_KEY 1 [7:0]								0x00
0x00 4811		OPT9	TMU_KEY 2 [7:0]								0x00
0x00 4812		OPT10	TMU_KEY 3 [7:0]								0x00
0x00 4813		OPT11	TMU_KEY 4 [7:0]								0x00
0x00 4814		OPT12	TMU_KEY 5 [7:0]								0x00
0x00 4815		OPT13	TMU_KEY 6 [7:0]								0x00
0x00 4816		OPT14	TMU_KEY 7 [7:0]								0x00
0x00 4817		OPT15	TMU_KEY 8 [7:0]								0x00
0x00 4818		OPT16	TMU_MAXATT [7:0]								0xC7
0x00 4819 to 487D	Reserved										
0x00 487E	Boot-loader(1)	OPT17	BL [7:0]								0x00
0x00 487F		NOPT17	NBL[7:0]								0xFF

1. This option consists of two bytes that must have a complementary value in order to be valid. If the option is invalid, it has no effect on EMC reset.

10.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 7*.

Figure 7. Pin input voltage



10.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 17. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
V_{DDx} - V_{SS}	Supply voltage (including V_{DDA} and V_{DDIO})(1)	-0.3	6.5	V
V_{IN}	Input voltage on true open drain pins (PE1, PE2)(2)	V_{SS} - 0.3	6.5	V
	Input voltage on any other pin(2)	V_{SS} - 0.3	V_{DD} + 0.3	
$\lvert V_{DDx} - V_{DD} \rvert$	Variations between different power pins	-	50	mV
$\lvert V_{SSx} - V_{SS} \rvert$	Variations between all the different ground pins	-	50	
V_{ESD}	Electrostatic discharge voltage	see *Absolute maximum ratings (electrical sensitivity) on page 76*		

1. All power (V_{DD}, V_{DDIO}, V_{DDA}) and ground (V_{SS}, V_{SSIO}, V_{SSA}) pins must always be connected to the external power supply
2. $I_{INJ(PIN)}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{INJ(PIN)}$ value. A positive injection is induced by $V_{IN} > V_{DD}$ while a negative injection is induced by $V_{IN} < V_{SS}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

Table 18. Current characteristics

Symbol	Ratings	Max.	Unit
I_{VDDIO}	Total current into V_{DDIO} power lines (source)(1)(2)(3)	100	mA
I_{VSSIO}	Total current out of $V_{SS\ IO}$ ground lines (sink)(1)(2)(3)	100	
I_{IO}	Output current sunk by any I/O and control pin	20	
	Output current source by any I/Os and control pin	-20	
$I_{INJ(PIN)}$(4)	Injected current on any pin	±10	
$I_{INJ(TOT)}$	Sum of injected currents	50	

1. All power (V_{DD}, V_{DDIO}, V_{DDA}) and ground (V_{SS}, V_{SSIO}, V_{SSA}) pins must always be connected to the external supply.
2. The total limit applies to the sum of operation and injected currents.
3. V_{DDIO} includes the sum of the positive injection currents. V_{SSIO} includes the sum of the negative injection currents.
4. This condition is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{INJ(PIN)}$ value. A positive injection is induced by $V_{IN} > V_{DD}$ while a negative injection is induced by $V_{IN} < V_{SS}$. For true open-drain pads, there is no positive injection current allowed and the corresponding V_{IN} maximum must always be respected.

Table 19. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	-65 to 150	°C
T_J	Maximum junction temperature	160	

Table 20. Operating lifetime(1)

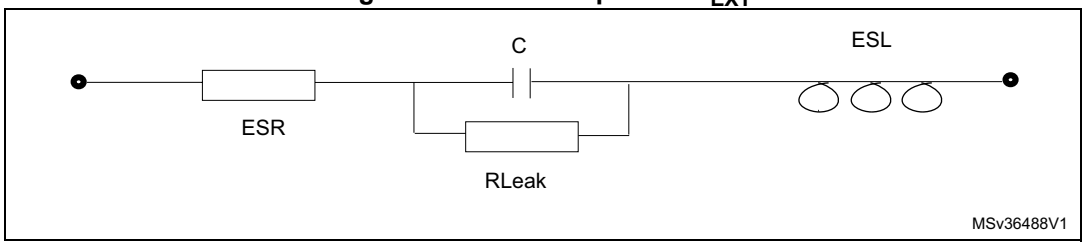
Symbol	Ratings	Value	Unit
OLF	Conforming to AEC-Q100 rev G	-40 to 125 °C	Grade 1
		-40 to 150 °C	Grade 0

1. For detailed mission profile analysis, please contact the nearest local ST Sales Office.

10.3.1 VCAP external capacitor

Stabilization for the main regulator is achieved connecting an external capacitor C_{EXT} to the V_{CAP} pin. C_{EXT} is specified in *Table 21*. Care should be taken to limit the series inductance to less than 15 nH.

Figure 9. External capacitor C_{EXT}



1. Legend: ESR is the equivalent series resistance and ESL is the equivalent inductance.

10.3.2 Supply current characteristics

The current consumption is measured as described in *Figure 6 on page 49* and *Figure 7 on page 50*.

If not explicitly stated, general conditions of temperature and voltage apply.

Table 23. Total current consumption in Run, Wait and Slow mode. General conditions for V_{DD} apply, T_A = -40 to 150 °C

Symbol	Parameter	Conditions		Typ	Max	Unit
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from Flash program memory, HSE external clock (without resonator)	f_{CPU} = 16 MHz	7.4	14	mA
			f_{CPU} = 8 MHz	4.0	7.4(2)	
			f_{CPU} = 4 MHz	2.4	4.1(2)	
			f_{CPU} = 2 MHz	1.5	2.5	
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from RAM and EEPROM, HSE external clock (without resonator)	f_{CPU} = 16 MHz	3.7	5.0	
			f_{CPU} = 8 MHz	2.2	3.0(2)	
			f_{CPU} = 4 MHz	1.4	2.0(2)	
			f_{CPU} = 2 MHz	1.0	1.5	
$I_{DD(WFI)}$(1)	Supply current in Wait mode	CPU stopped, all peripherals off, HSE external clock	f_{CPU} = 16 MHz	1.65	2.5	
			f_{CPU} = 8 MHz	1.15	1.9(2)	
			f_{CPU} = 4 MHz	0.90	1.6(2)	
			f_{CPU} = 2 MHz	0.80	1.5	
$I_{DD(SLOW)}$(1)	Supply current in Slow mode	f_{CPU} scaled down, all peripherals off, code executed from RAM	Ext. clock 16 MHz f_{CPU} = 125 kHz	1.50	1.95	
			LSI internal RC f_{CPU} = 128 kHz	1.50	1.80(2)	

1. The current due to I/O utilization is not taken into account in these values.
2. Values not tested in production. Design guidelines only.

Figure 12. Typ. $I_{DD(RUN)HSI}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = off

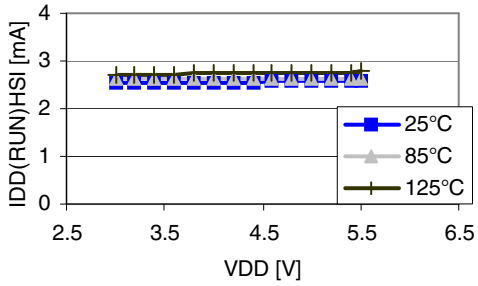


Figure 13. Typ. $I_{DD(WFI)HSE}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = on

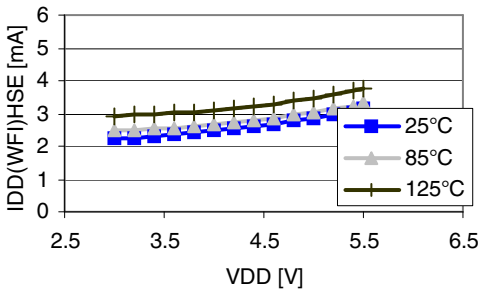


Figure 14. Typ. $I_{DD(WFI)HSE}$ vs. f_{CPU} @ V_{DD} = 5.0 V, peripheral = on

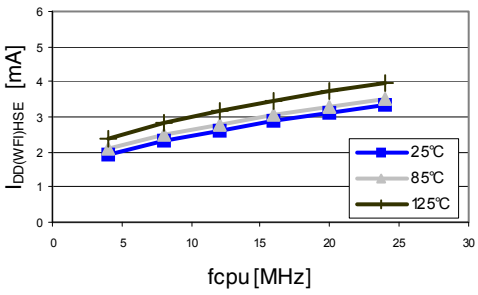
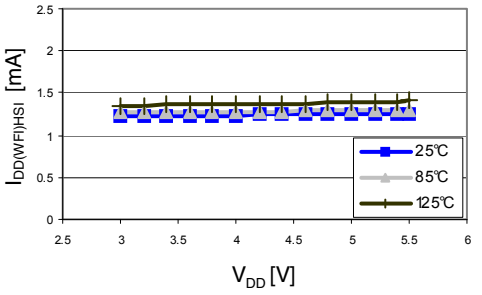


Figure 15. Typ. $I_{DD(WFI)HSI}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = off



10.3.3 External clock sources and timing characteristics

HSE user external clock

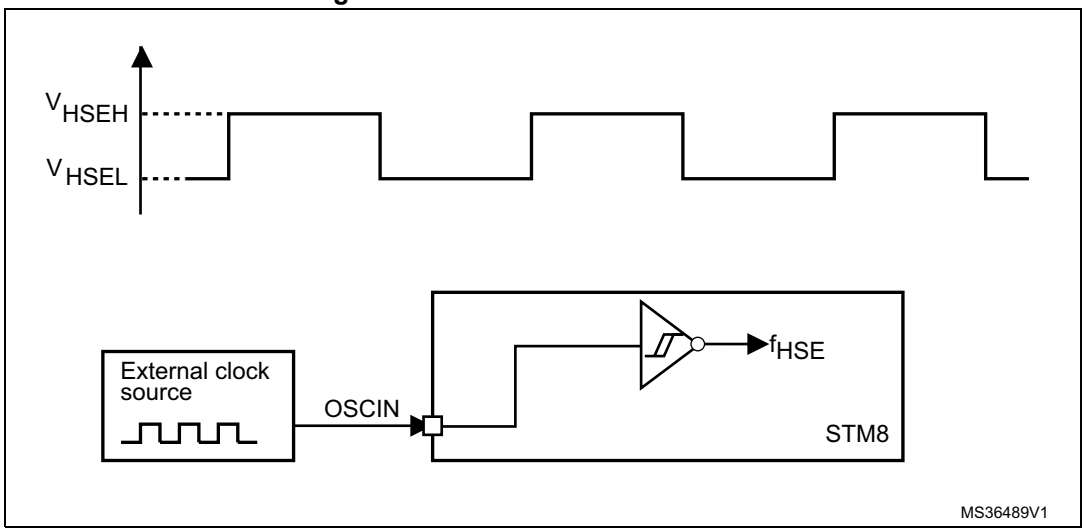
Subject to general operating conditions for V_{DD} and T_A.

Table 28. HSE user external clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	User external clock source frequency	T_A is -40 to 150 °C	0(1)	-	16	MHz
V_{HSEdHL}	Comparator hysteresis	-	0.1 x V_{DD}	-	-	V
V_{HSEH}	OSCIN input pin high level voltage	-	0.7 x V_{DD}	-	V_{DD}	
V_{HSEL}	OSCIN input pin low level voltage	-	V_{SS}	-	0.3 x V_{DD}	
I_{LEAK_HSE}	OSCIN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-1	-	+1	µA

1. In CSS is used, the external clock must have a frequency above 500 kHz.

Figure 16. HSE external clock source



HSE crystal/ceramic resonator oscillator

The HSE clock can be supplied using a crystal/ceramic resonator oscillator of up to 16 MHz. All the information given in this paragraph is based on characterization results with specified typical external components. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details (frequency, package, accuracy...).

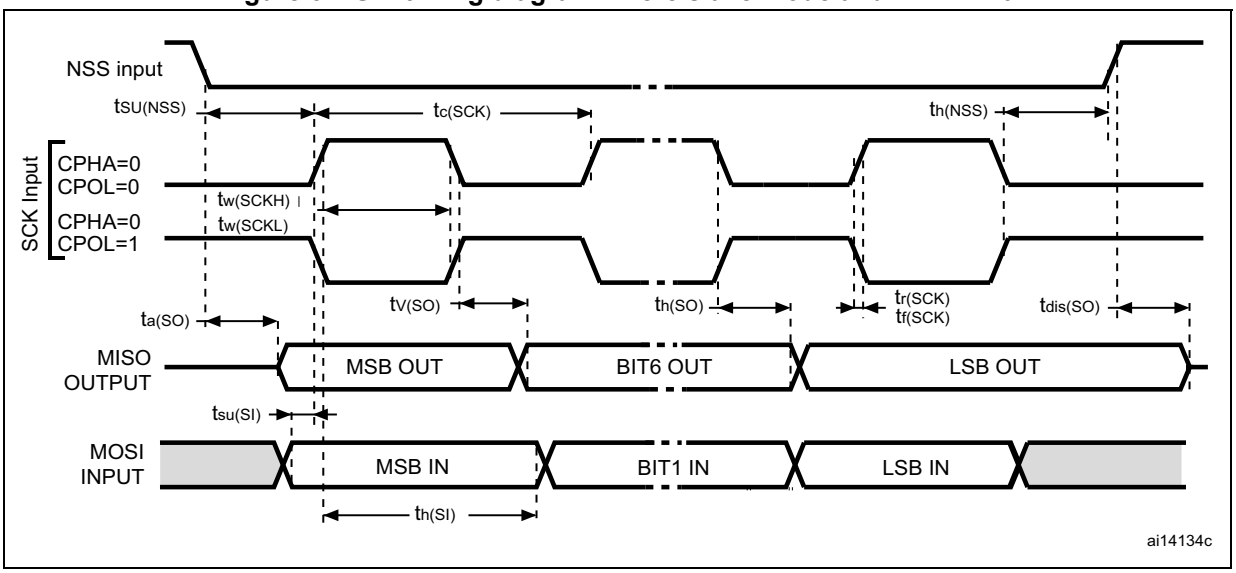
Table 29. HSE oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R_F	Feedback resistor	-	-	220	-	kΩ
C_{L1}/C_{L2}(1)	Recommended load capacitance	-	-	-	20	pF
g_m	Oscillator transconductance	-	5	-	-	mA/V
$t_{SU(HSE)}$(2)	Startup time	V_{DD} is stabilized	-	2.8	-	ms

1. The oscillator needs two load capacitors, C_{L1} and C_{L2}, to act as load for the crystal. The total load capacitance (C_{load}) is $(C_{L1} * C_{L2})/(C_{L1} + C_{L2})$. If $C_{L1} = C_{L2}$, $C_{load} = C_{L1} / 2$. Some oscillators have built-in load capacitors, C_{L1} and C_{L2}.
2. This value is the startup time, measured from the moment it is enabled (by software) until a stabilized 16 MHz oscillation is reached. It can vary with the crystal type that is used.

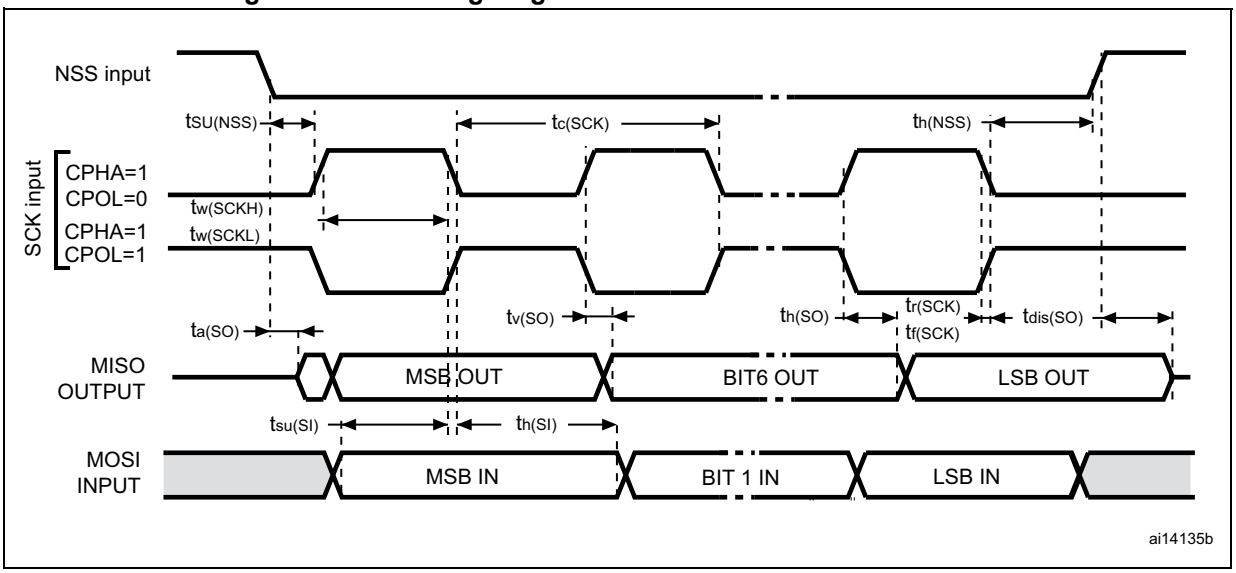
3. Values based on design simulation and/or characterization results, and not tested in production.
4. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
5. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z.

Figure 37. SPI timing diagram where slave mode and CPHA = 0



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Figure 38. SPI timing diagram where slave mode and CPHA = 1



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

10.3.10 I²C interface characteristics

Table 39. I²C characteristics

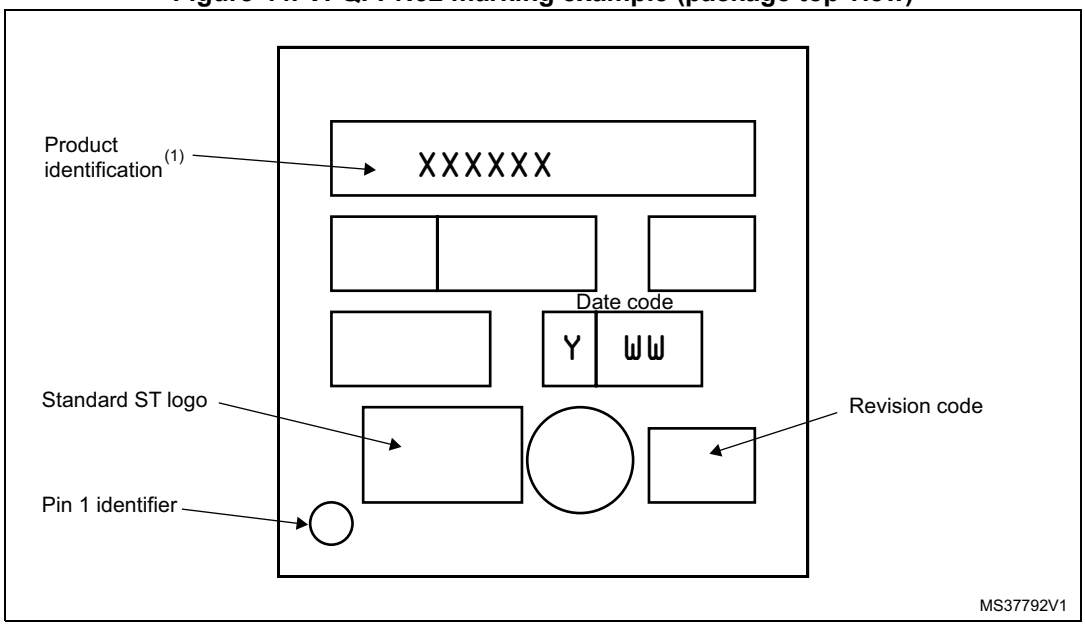
Symbol	Parameter	Standard mode I²C		Fast mode I²C(1)		Unit
		Min(2)	Max(2)	Min(2)	Max(2)	
$t_{w(SCLL)}$	SCL clock low time	4.7	-	1.3	-	µs
$t_{w(SCLH)}$	SCL clock high time	4.0	-	0.6	-	
$t_{su(SDA)}$	SDA setup time	250	-	100	-	ns
$t_{h(SDA)}$	SDA data hold time	0(3)	-	0(4)	900(3)	
$t_{r(SDA)}$ $t_{r(SCL)}$	SDA and SCL rise time (V_{DD} = 3 to 5.5 V)	-	1000	-	300	
$t_{f(SDA)}$ $t_{f(SCL)}$	SDA and SCL fall time (V_{DD} = 3 to 5.5 V)	-	300	-	300	
$t_{h(STA)}$	START condition hold time	4.0	-	0.6	-	µs
$t_{su(STA)}$	Repeated START condition setup time	4.7	-	0.6	-	
$t_{su(STO)}$	STOP condition setup time	4.0	-	0.6	-	
$t_{w(STO:STA)}$	STOP to START condition time (bus free)	4.7	-	1.3	-	
C_b	Capacitive load for each bus line	-	400	-	400	pF

1. f_{MASTER}, must be at least 8 MHz to achieve max fast I²C speed (400 kHz)
2. Data based on standard I²C protocol requirement, not tested in production
3. The maximum hold time of the start condition has only to be met if the interface does not stretch the low time
4. The device must internally provide a hold time of at least 300 ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL

Device marking

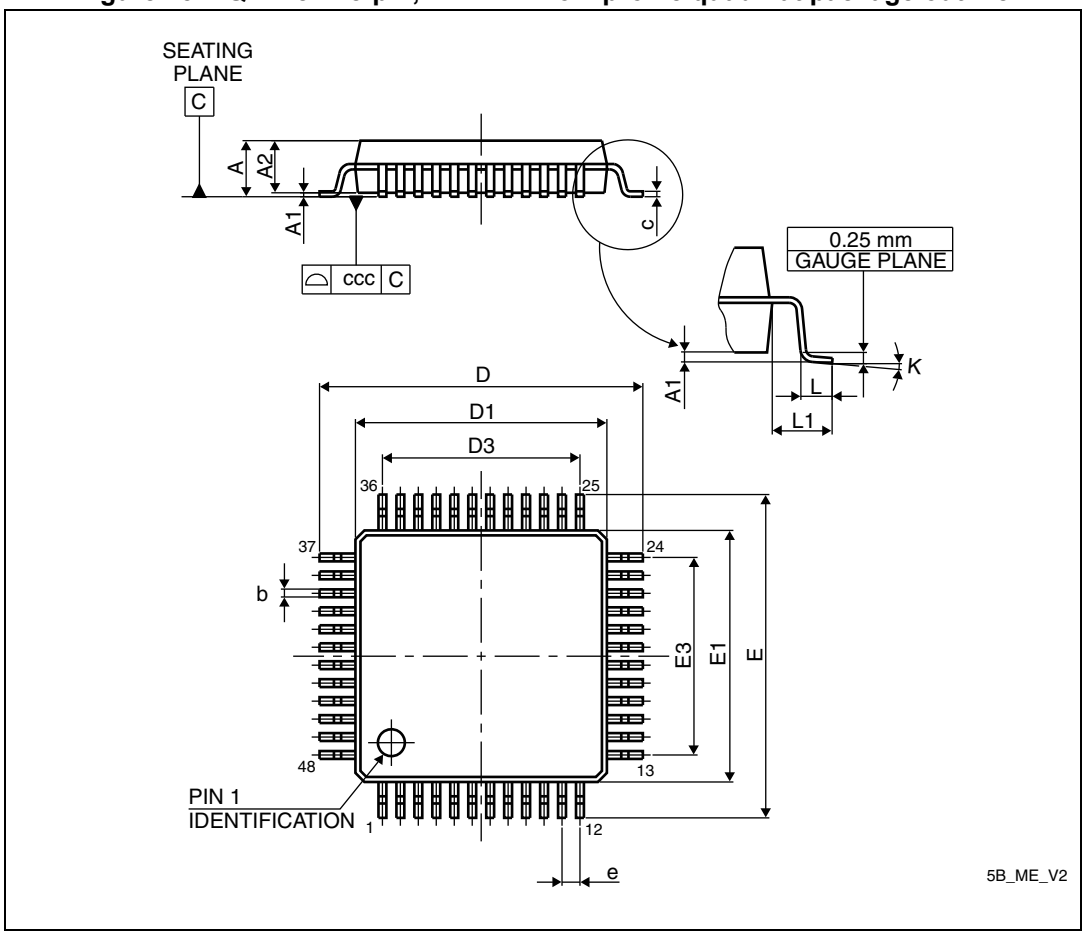
The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 44. VFQFPN32 marking example (package top view)



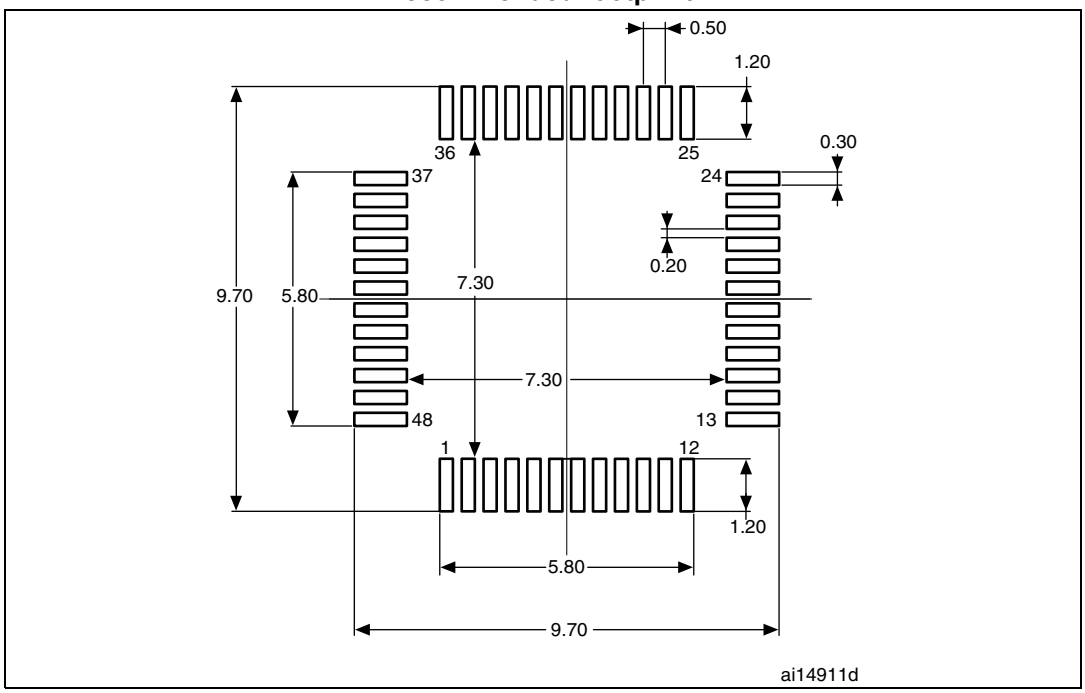
11.2 LQFP48 package information

Figure 45. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

Figure 46. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package recommended footprint

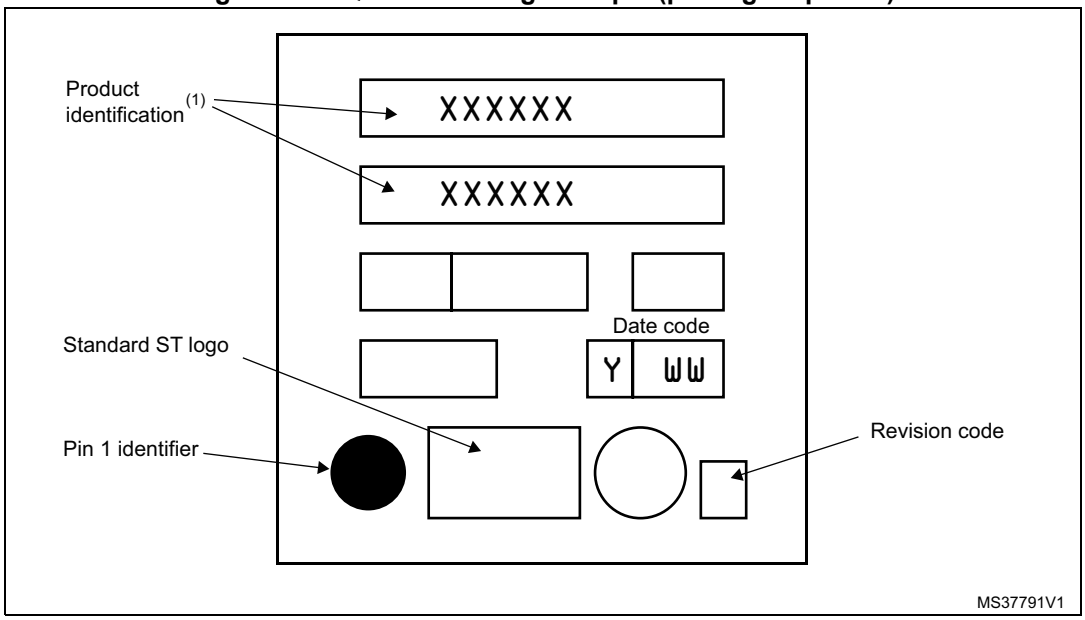


1. Dimensions are expressed in millimeters.

Device marking

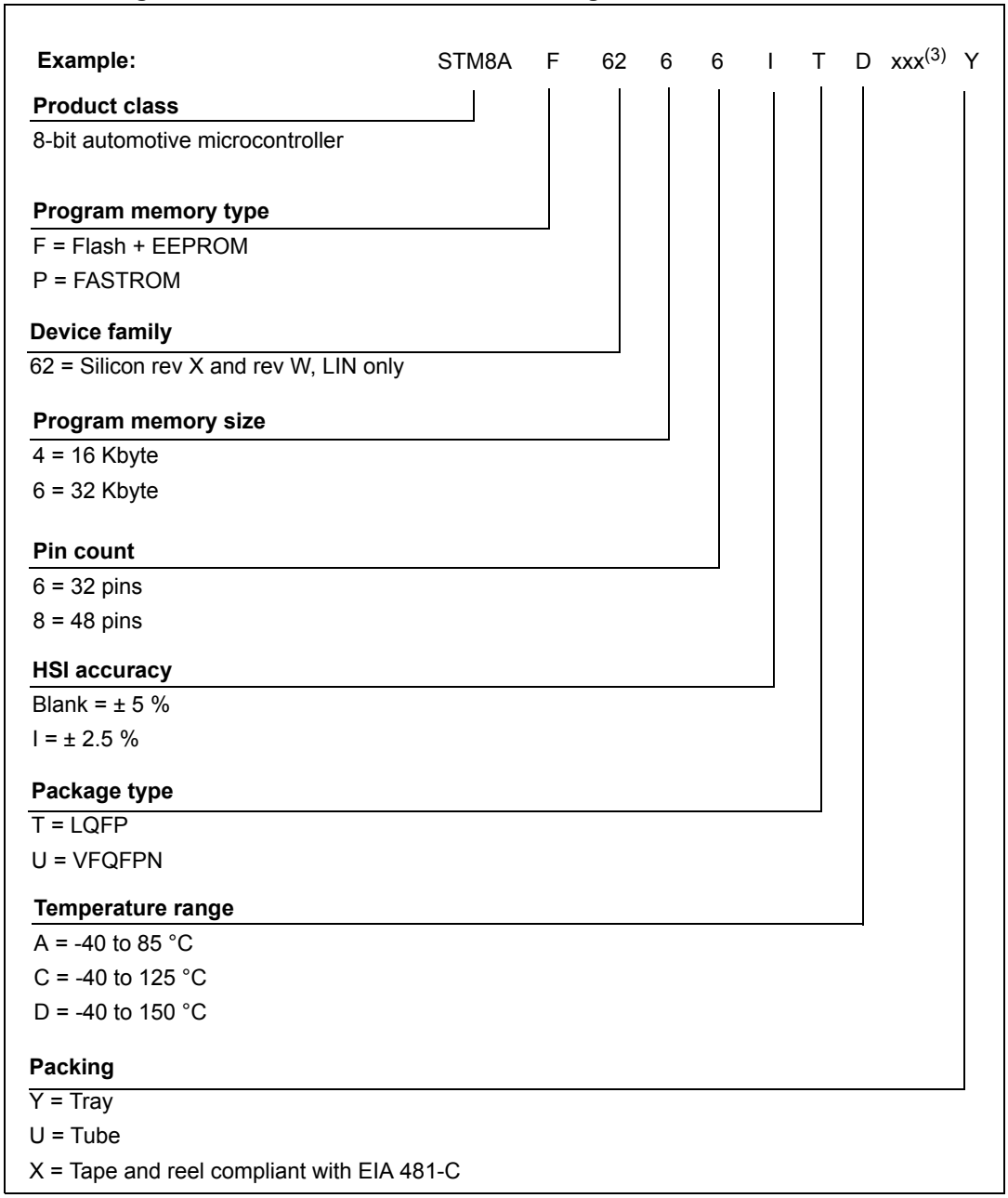
The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 47. LQFP48 marking example (package top view)



12 Ordering information

Figure 51. STM8AF6246/48/66/68 ordering information scheme(1) (2)



1. For a list of available options (e.g. memory size, package) and orderable part numbers or for further information on any aspect of this device, please go to *www.st.com* or contact the nearest ST Sales Office.
2. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.
3. Customer specific FASTROM code or custom device configuration. This field shows ‘SSS’ if the device contains a super set silicon, usually equipped with bigger memory and more I/Os. This silicon is supposed to be replaced later by the target silicon.

Table 50. Document revision history (continued)

Date	Revision	Changes
31-Jan-2011	5	Modified references to reference manual, and Flash programming manual in the whole document. Added reference to AEC Q100 standard on cover page. Renamed timer types as follows: – Auto-reload timer to general purpose timer – Multipurpose timer to advanced control timer – System timer to basic timer Introduced concept of medium density Flash program memory. Updated timer names in *Figure: STM8A block diagram.* Added TMU brief description in *Section: Flash program and data EEPROM*, and updated TMU_MAXATT description in *Table: Option byte description*. Updated clock sources in clock controller features. Changed 16MHZTRIM0 to HSITRIM bit in *Section: User trimming.* Added *Table: Peripheral clock gating bits.* Updated *Section: Low-power operating modes.* Added calibration using TIM3 in *Section: Auto-wakeup counter.* Added *Table: ADC naming* and *Table: Communication peripheral naming correspondence.* Added *Note 1* related AIN12 pin in *Section: Analog-to-digital converter (ADC)* and *Table: STM8AF61xx/62xx (32 Kbyte) microcontroller pin description.* Updated SPI data rate to 10 Mbit/s or $f_{MASTER}/2$ in *Section: Serial peripheral interface (SPI).* Added reset state in *Table: Legend/abbreviation.* *Table: STM8AF61xx/62xx (32 Kbyte) microcontroller pin description:* added *Note 7* related to PD1/SWIM, modified *Note 6,* corrected wpu input for PE1 and PE2, and renamed TIMn_CCx and TIMn_NCCx to TIMn_CHx and TIMn_CHxN, respectively. ***Section: Register map:*** Replaced tables describing register maps and reset values for non-volatile memory, global configuration, reset status, clock controller, interrupt controller, timers, communication interfaces, and ADC, by *Table: General hardware register map*. Added *Note 1* for Px_IDR registers in *Table: I/O port hardware register map.* Updated register reset values for Px_IDR registers. Added SWIM and debug module register map.

Table 50. Document revision history (continued)

Date	Revision	Changes
18-Jul-2012	6 (continued)	*Section: Reset pin characteristics:* updated text below *Figure: Typical NRST pull-up current Ipu vs VDD*. *Figure: Recommended reset pin protection*: updated unit of capacitor. *Table: SPI characteristics:* updated SCK high and low time conditions and values. *Figure: SPI timing diagram - master mode*: replaced 'SCK input' signals with 'SCK output' signals. Updated *Table: VFQFPN 32-lead very thin fine pitch quad flat no-lead package mechanical data, Table: LQFP 48-pin low profile quad flat package mechanical data*, and *Table: LQFP 32-pin low profile quad flat package mechanical data.* Replaced *Figure: LQFP 48-pin low profile quad flat package (7 x 7)* and *Figure: LQFP 32-pin low profile quad flat package (7 x 7)*. Added *Figure: LQFP 48-pin recommended footprint* and *Figure: LQFP 32-pin recommended footprint.* *Figure: Ordering information scheme(1):* added footnote *1*, added "xxx" and footnote *2*, updated example and device family; added FASTROM. *Section: C and assembly toolchains:* added www.iar.com
04-Apr-2014	7	Updated: – *Table: Device summary,* – *Table: STM8AF62xx product line-up,* – *Table: STM8AF/H61xx product line-up.* – SPI description in *Features.* – The typical and maximum values for t_{TEMP} reset release delay in *Table: Operating conditions at power-up/power-down.* – The symbol for NRST Input not filtered pulse duration in *Table: NRST pin characteristics* – The address and comment of Reset interrupt in *Table: STM8A interrupt table.* Added the three footnotes to *Figure VFQFPN 32-lead very thin fine pitch quad flat no-lead package (5 x 5)*.
24-Jun-2014	8	Updated *Table: HSI oscillator characteristics.* Added HSI accuracy and removed temperature range B in *Figure: Ordering information scheme(1).*
12-Nov-2014	9	Updates in *Table: HSI oscillator characteristics* (HSI oscillator accuracy (factory calibrated) values) and *Figure: Ordering information scheme(1)* (changed the value for I).